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Judul:

Defects in microelectronic materials and devices

Pengarang/Penulis:

Subjek:

Microelectronics -- Materials -- Testing; Metal oxide semiconductor field -- Effect transistors -- Testing; Integrated circuits -- Defects

Nomor Panggil:

621.381 DEF

Penerbitan:

CRC Press, Taylor & Francis Group

Link Terkait:

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